					Docket Number (Optional) P 6121.13044		Application Number 10/666,445		
INFORMATION DISCLOSURE CITATION					Applicant(s) Artur G. Olszak and Chen Liang				
(Use several sheets if necessary)					Filing Date Group Art Unit				
JAN 12 ADD				September 19,		003	2878		
U.S. PATENT DOCUMENTS EXAMINE REF DOCUMENT NUMBER DATE NAME CLASS SUBCLASS FILING DATE INITIAL REF DOCUMENT NUMBER DATE NAME									
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